

# INTERNATIONAL SEARCH REPORT

Inte Application No  
PCT/IB2005/050509

A. CLASSIFICATION OF SUBJECT MATTER  
IPC 7 G06F1/00 H04L9/06

According to International Patent Classification (IPC) or to both national classification and IPC

## B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)  
IPC 7 G06F H04L

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Electronic data base consulted during the international search (name of data base and, where practical, search terms used)  
EPO-Internal

## C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	US 2003/132777 A1 (LAACKMANN PETER ET AL) 17 July 2003 (2003-07-17) the whole document	1-10
X	US 2003/218475 A1 (GAMMEL BERNDT) 27 November 2003 (2003-11-27) the whole document	1-10
X	US 5 861 652 A (COLE ET AL) 19 January 1999 (1999-01-19) the whole document	1-10
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☒ Further documents are listed in the continuation of box C.

☒ Patent family members are listed in annex.--

### \* Special categories of cited documents :

- \*A\* document defining the general state of the art which is not considered to be of particular relevance
- \*E\* earlier document but published on or after the international filing date
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- \*O\* document referring to an oral disclosure, use, exhibition or other means
- \*P\* document published prior to the international filing date but later than the priority date claimed

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- \*X\* document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone
- \*Y\* document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art.
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Date of the actual completion of the international search

17 May 2005

Date of mailing of the international search report

25/05/2005

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 Int. I Application No  
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C.(Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT		
Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
A	<p>CHEN J C ET AL: "An on-chip,-interconnect capacitance characterization method with sub-femto-farad resolution"</p> <p>IEEE TRANSACTIONS ON SEMICONDUCTOR MANUFACTURING, IEEE INC, NEW YORK, US, vol. 11, no. 2, 1 May 1998 (1998-05-01), pages 204-210, XP002096116</p> <p>ISSN: 0894-6507</p> <p>the whole document</p>	1-10
A	<p>LAQUAI B ET AL: "A new method and test structure for easy determination of femto-farad on-chip capacitances in a MOS process"</p> <p>PROCEEDINGS OF THE INTERNATIONAL CONFERENCE ON MICROELECTRONIC TEST STRUCTURES (ICMTS). SAN DIEGO, MAR. 16 - 19, 1992, NEW YORK, IEEE, US, 16 March 1992 (1992-03-16), pages 62-66, XP010059392</p> <p>ISBN: 0-7803-0535-3</p> <p>the whole document</p>	1-10
A	<p>KHALKHAL A ET AL: "ON-CHIP MEASUREMENT OF INTERCONNECT CAPACITANCES IN A CMOS PROCESS"</p> <p>PROCEEDINGS OF THE INTERNATIONAL CONFERENCE ON MICROELECTRONIC TEST STRUCTURES (ICMTS). NARA, JP., MAR. 22 - 25, 1995, NEW YORK, IEEE, US, 22 March 1995 (1995-03-22), pages 145-149, XP000547658</p> <p>ISBN: 0-7803-2066-2</p> <p>the whole document</p>	1-10
A	<p>ANDERSON R ET AL: "TAMPER RESISTANCE - A CAUTIONARY NOTE"</p> <p>PROCEEDINGS OF THE USENIX WORKSHOP OF ELECTRONIC COMMERCE, November 1996 (1996-11), pages 1-11, XP000923039</p> <p>the whole document</p>	1-10
A	<p>LASH T: "A STUDY OF POWER ANALYSIS AND THE ADVANCED ENCRYPTION STANDARD"</p> <p>MS SCHOLARLY PAPER GEORGE MASON UNIVERSITY, February 2002 (2002-02), pages A-B,1, XP001130987</p> <p>the whole document</p>	1-10

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